

IGBT3 Chip

Features:

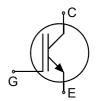
- 650V Trench & Field Stop technology
- low V_{CE(sat)}
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling
- Qualified according to JEDEC for target applications

Recommended for:

• power modules

Applications:

• drives



Chip Type	V _{CE}	/ Cn ¹⁾	Die Size	Package
SIGC40T65R3E	650V	75A	5.74 x 6.96 mm ²	sawn on foil

¹⁾ nominal collector current at Tc = 100°C, not subject to production test - verified by design/characterization

Mechanical Parameters

Meenamearranamet		F	-	
Die size		5.74 x 6.96		
Emitter pad size (incl. gate pad)		See chip drawing	mm ²	
Gate pad size		1.615 x 0.817	mm	
Area total		39.95		
Thickness		70	μm	
Wafer size		200	mm	
Max.possible chips pe	er wafer	666	·	
Passivation frontside		Photoimide		
Pad metal		3200 nm AlSiCu		
Backside metal		Ni Ag –system		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		AI, <500µm		
Reject ink dot size		Ø 0.65mm ; max 1.2mm		
	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 2 < 6 month		
Storage environment	for open MBB bags	Acc. to IEC62258-3: Atmosphere >99% Nitrogen of Humidity <25%RH, Temperature 17°C – 25°C, <		



Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-Emitter voltage, <i>T</i> _{vj} =25 °C	V _{CE}	650	V
DC collector current, limited by $T_{vj max}$	I _c	1)	А
Pulsed collector current, t_p limited by $T_{vj \max}^{2}$	I _{c,puls}	225	А
Gate emitter voltage	V _{GE}	±20	V
Operating junction temperature	T _{vj}	-40 +175	°C
Short circuit data ²) ³⁾ V_{GE} = 15V, V_{CC} = 360V, T_{vj} = 150°C	t _{sc}	6	μs

¹⁾ depending on thermal properties of assembly

²) not subject to production test - verified by design/characterization

³⁾ allowed number of short circuits: <1000; time between short circuits: >1s.

Static Characteristics (tested on wafer), T_{vi} =25 °C

Parameter	Symbol	Conditions	Value			Unit
	Cymbol		min.	typ.	max.	
Collector-Emitter breakdown voltage	V _{(BR)CES}	V _{GE} =0V , <i>I</i> _C =4 mA	650			
Collector-Emitter saturation voltage	V _{CEsat}	V _{GE} =15V, <i>I</i> _C =75A	0.93	1.45	1.77	V
Gate-Emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =1.2mA , $V_{\rm GE}$ = $V_{\rm CE}$	5.1	5.8	6.4	
Zero gate voltage collector current	I _{CES}	V _{CE} =650V , V _{GE} =0V			3.8	μA
Gate-Emitter leakage current	I _{GES}	V _{CE} =0V , V _{GE} =20V			600	nA
Integrated gate resistor	r _G			4		Ω

Electrical Characteristics (not subject to production test - verified by design / characterization)

Parameter	Symbol	Conditions	Value			Unit
Falameter	Symbol		min.	typ.	max.	
Collector Emitter acturation voltage	V	V _{GE} =15V, <i>I</i> _C =75A,		tha		V
Collector-Emitter saturation voltage	V _{CEsat}	<i>T</i> _{vj} =175 °C		tbd		v
Input capacitance	Cies	V _{CE} =25V,		4620		
		V _{GE} =0V, <i>f</i> =1MHz				pF
Reverse transfer capacitance	C _{res}	$T_{\rm vj}$ =25 °C		137		



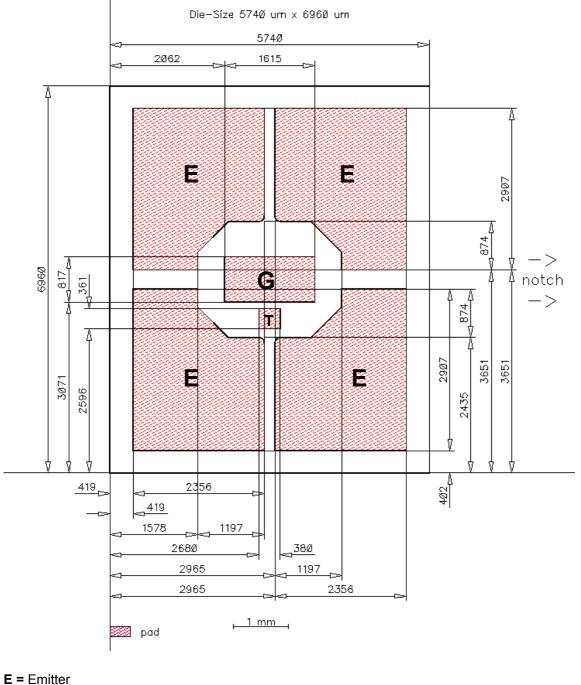
Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

This chip data sheet refers to the device data sheet	tbd	tbd
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Chip Drawing



- G = Gate
- T = Test pad do not contact



Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date

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